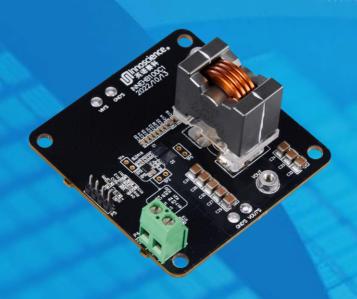


INNEHB100C1

Evaluation Board Manual
100V GaN HEMT INN100W027A
Open Loop Half-Bridge EVB







CAUTION

Please carefully read the following content since it contains critical information about safety and the possible hazard it may cause by incorrect use.



ELECTRICAL SHOCK HAZARD

There is a dangerous voltage on the demo board, and exposure to high voltage may lead to safety problems such as injury or death.

Proper operating and safety procedures must be adhered to and used only for laboratory evaluation demonstrations and not directly to end-user equipment.



M HOT SURFACE

The surface of PCB can be hot and could cause burns. DO NOT TOUCH THE PCB WHILE OPERATING!!

REMINDER

This product contains parts that are susceptible to electrostatic discharge (ESD). When using this product, be sure to follow antistatic procedures.





Contents

1. Overview	1
1.1. Introduction	1
1.2. Test Equipment Requirement	1
2. Performance summary	2
3. Block Diagram	3
4. EVB Overview	4
5. Evaluation Results	5
5.1. Efficiency Results	5
5.2. Thermal performance	5
5.3. Switching Waveforms	6
Appendix	7
Appendix A. Testing guidance	7
Appendix B. Schematic	12
Appendix C. PCB Layout	13
Appendix D. BOM	
Revision History	17



1. Overview

1.1. Introduction

INNEHB100C1 is a half-bridge evaluation board equipped with the half-bridge gate driver to evaluate the performance of 100V GaN HEMT INN100W027A. This board can simplify the test process, it can easily realize Buck converter with single or dual PWM input. The evaluation board can be used in BUCK circuit frequency range of 400kHz to 800kHz, input voltage range of 36V to 80V, under the frequency of 600kHz and the wind speed of 1400LFM, 48V-12V full load 23A efficiency can reach 96.70%. The board can be used not only for BUCK circuits, but also for BOOST circuits. The board includes all the necessary information you need, and the layout has been optimized to achieve the best performance. Test points are also included for the waveform measurement and efficiency evaluation.

1.2. Test Equipment Requirement

To evaluate the performance properly, you need to prepare the following test equipment:

- 1) High speed digital oscilloscope (≥500MHz Bandwidth)
- 2) Two low voltage DC power supply
- 3) PWM generator
- 4) Digital Multimeter
- 5) DC load (E-load or Power Resistor)



2. Performance summary

The electrical characteristics of INNEHB100C1 are shown in Table 1.

Table 1 Electrical Characteristic (T_A=25℃)

Symbol	Parameters	Min	Тур	Max	Units
V_{DD}	V _{DD} supply Voltage	7	8	12	V
V _{IN}	Input Voltage	36	48	80 ⁽¹⁾	V
F _{SW}	Switching frequency		600		kHz
Роит	Output Power			330 ⁽²⁾	W
EFF	Typical efficiency		96.70%(3)		
	Input Logic 'High'	3.5		5	V
V_{PWM}	Input Logic 'Low'	0		1.5	V

⁽¹⁾ Maximum input voltage depends on inductive loading, maximum switch node ringing must be kept under 100 V for INN100W027A.

⁽²⁾ Maximum output power with be subject to switching frequency, bus voltage, load current, EVB temperature and thermal cooling.

^{(3) 96.70%} is the efficiency at 48V to 12V, load 23A, frequency 600 kHz, and the wind speed of 1400LFM.



3. Block Diagram

The system block diagram of INNEHB100C1 is shown in Figure 1.

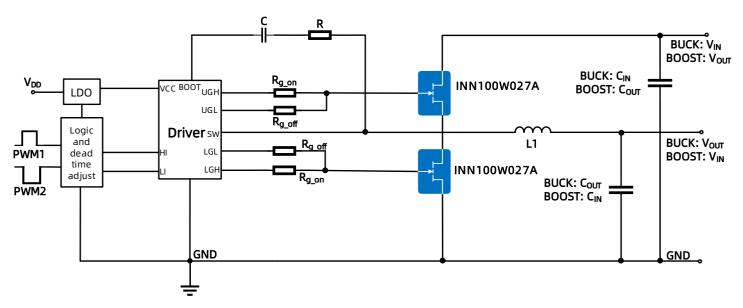


Figure 1 INNEHB100C1 Block Diagram



4. EVB Overview

The top and bottom views of the INNEHB100E1 board are shown in **Figure**2 and **Figure 3**.

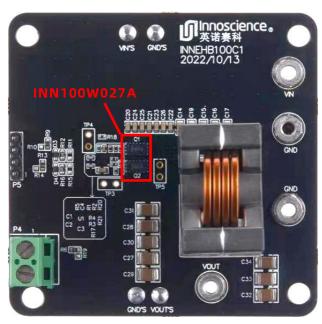


Figure 2 Top view of INNEHB100C1

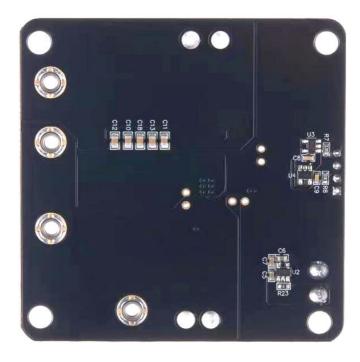
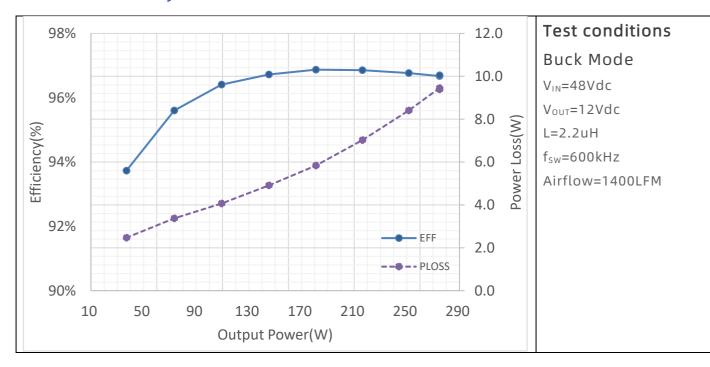


Figure 3 Bottom view of INNEHB100C1

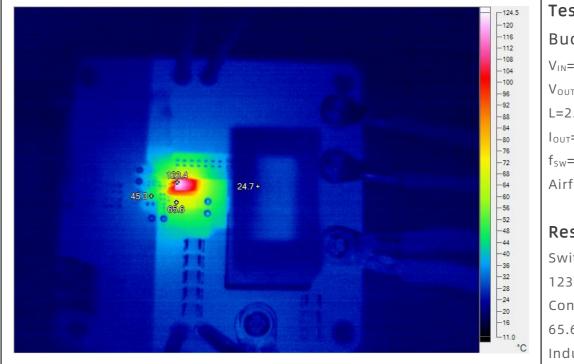


5. Evaluation Results

5.1. Efficiency Results



5.2. Thermal performance



Test conditions Buck Mode

V_{IN}=48Vdc

V_{OUT}=12Vdc

L=2.2uH

I_{OUT}=23A

 $f_{SW}=600kHz$

Airflow=1400LFM

Result

Switching GaN:

123.4℃

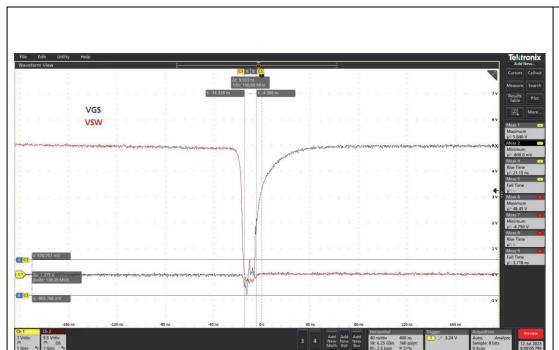
Continuation GaN:

65.6℃

Inductor: 24.7℃



5.3. Switching Waveforms



Test conditions

Buck Mode

V_{IN}=48Vdc

V_{out}=12Vdc

Ι_{ΟΙΙΤ}=23Α

 $f_{SW}=600kHz$

Airflow=1400LFM

 $R_{g_on}=2.2\Omega$, $R_{g_off}=0\Omega$

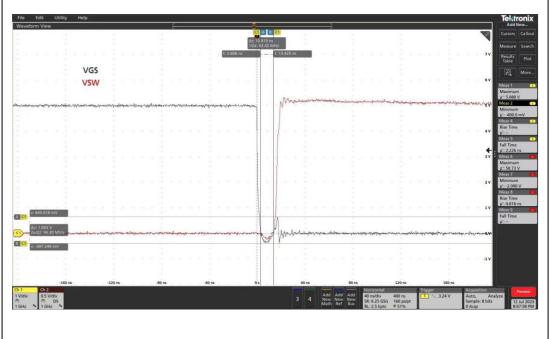
Result

SW Edge:

Falling time=3.718ns Falling Overshoot=-4.75V

LG Edge:

Rising time=21.15ns,



Test conditions

Buck Mode

V_{IN}=48Vdc

V_{OUT}=12Vdc

I_{OUT}=23A

 $f_{SW}=600kHz$

Airflow=1400LFM

 $R_{g \text{ on}}=2.2\Omega$, $R_{g \text{ off}}=0\Omega$

Result

SW Edge:

Rising Overshoot=2.73V Rising time=4.016ns

LG Edge:

Falling time=2.226ns

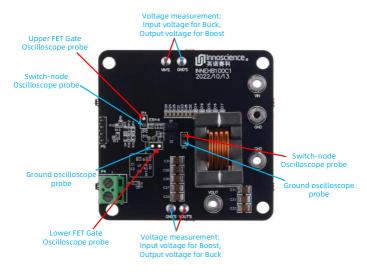


Appendix

Appendix A. Testing guidance

1、 Test point location

The test points of INNEHB100E1 are shown in Appendix Figure 1.

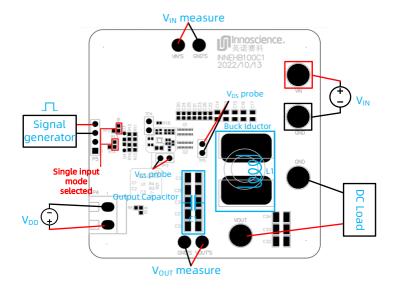


Appendix Figure 1 Measurement points

2、 Test setup

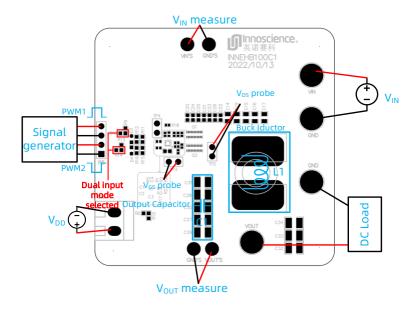
2.1 Buck Mode

In Buck mode, the wiring diagrams of INNEHB100E1 with single PWM input and dual PWM input are shown in **Appendix Figure 2** and **Appendix Figure 3**, respectively.



Appendix Figure 2 Single-PWM input Buck mode





Appendix Figure 3 Dual-PWM input Buck mode

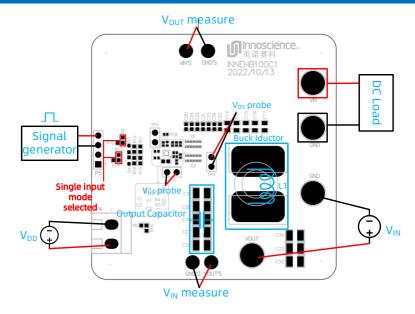
Before tests, single or dual PWM input modes could be selected. When selecting the single PWM input mode, please solder 0Ω resistor to R9 & R13. The dead time is regulated by R12, R16, C1 and C2. The value for R12 is 200Ω , and R16 is 360Ω . The value of C1 and C2 is 200 pF. At this time, at the load of 10A, the corresponding measured dead time between lower FET shutdown and upper FET opening is about 10ns, and the dead time between upper FET shutdown and lower FET opening is also about 10ns.

To select dual PWM mode, please solder 0Ω resistor to R10, R14, R12 and R16. **Appendix Figure 3** shows the required PWM signals; PWM1 and PWM2 should be complementary. The dead time is controlled by the signal generator.

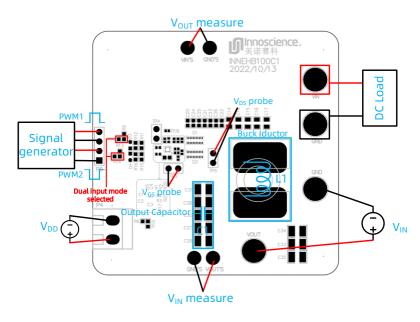
2.2 Boost Mode

In Boost mode, the wiring diagrams of INNEHB100E1 with single PWM input and dual PWM input are shown in **Appendix Figure 4** and **Appendix Figure 5**, respectively.





Appendix Figure 4 Single-PWM input Boost mode



Appendix Figure 5 Dual-PWM input Boost mode

- 3、 Power up and down sequence
 - 3.1 Power-up sequence (Buck Mode)
 - 1) Check every power supply is off.
 - 2) Connect the DC voltage source to terminal V_{IN} and common ground terminal GND, as shown in Appendix Figure 2 (Pay attention to the polarity).
 - 3) Connect the electronic load to pin Vout.
 - 4) Connect the auxiliary source to the V_{DD} terminal **P4** (Pay attention to the polarity).





- 5) Connect the signal generator to pin P5.
- 6) Turn on the auxiliary power supply. Note the voltage ranges from 7V ~ 12V.
- 7) Open the signal generator and enter the PWM signal with the required duty ratio and frequency.
- 8) Make sure the initial input supply voltage is 0 V, turn on the power and slowly increase the voltage to the desired value (do not exceed the absolute maximum voltage). Probe switch-node and view the switching operation.
- 9) Once operational, according to the heating state of the device slowly increase the load current, do not exceed the maximum temperature required by the device specification.

3.2 Power-up sequence (Boost Mode)

- 1) Check every power supply is **off**
- 2) Connect the DC voltage source to pin V_{OUT} , as shown in Appendix Figure 4 (Pay attention to the polarity).
- 3) Connect the positive pole of the electronic load to pin V_{IN} and the negative pole to pin GND.
- 4) Connect the auxiliary source to the V_{DD} terminal **P4** (Pay attention to the polarity).
- 5) Connect the signal generator to pin P5.
- 6) Turn on the auxiliary power supply. Note the voltage ranges from 7V ~ 12V.
- 7) Open the signal generator and enter the PWM signal with the required duty ratio and frequency.
- 8) Make sure the initial input supply voltage is 0 V, turn on the power and slowly increase the voltage to the desired value (do not exceed the absolute maximum voltage). Probe switch-node and view the switching operation.
- 9) Once operational, according to the heating state of the device slowly increase the load current, do not exceed the maximum temperature





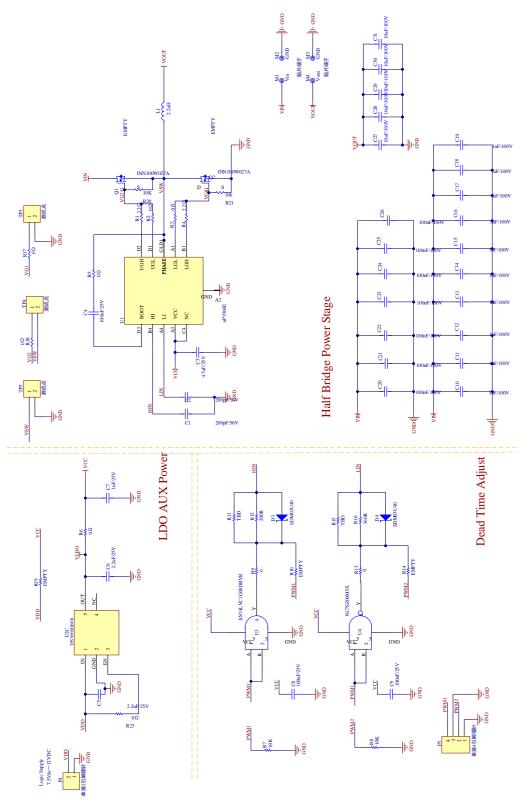
required by the device specification.

- 3.3 Power-down sequence
 - 1) Turn off the E-load first
 - 2) Turn off the DC voltage source
 - 3) Turn off the **PWM generator**
 - 4) Turn off the auxiliary power supply



Appendix B. Schematic

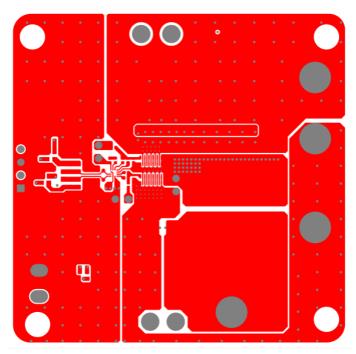
The schematic diagram of INNEHB100E1 is shown in **Appendix Figure 6**.



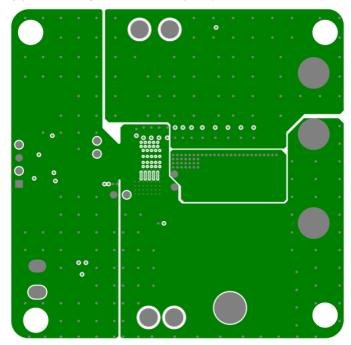
Appendix Figure 6 Schematic of INNEHB100C1



Appendix C. PCB Layout

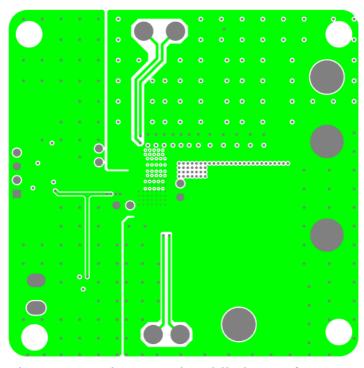


Appendix Figure 7 The top layer of INNEHB100C1

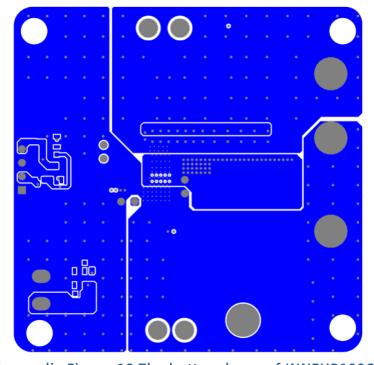


Appendix Figure 8 The first middle layer of INNEHB100C1



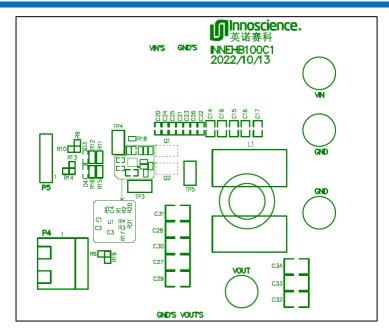


Appendix Figure 9 The second middle layer of INNEHB100C1

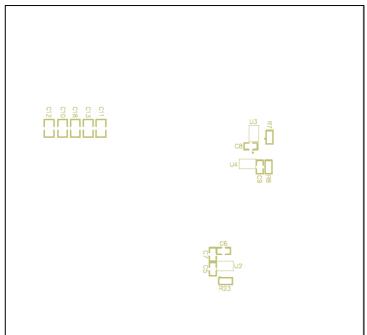


Appendix Figure 10 The bottom layer of INNEHB100C1





Appendix Figure 11 The top overlay of INNEHB100C1



Appendix Figure 12 The bottom overlay of INNEHB100C1





Appendix D. BOM

Designator	esignator Part Number Manufacturer Description		Quantity	
C1, C2	0402N201J500CT	WALSIN	CAP, 200pF/50V, ±5%, C0G	2
C3	TMK107BBJ475KA-T	TAIYO YUDEN	CAP, 4.7uF/25V, ±10%, X5R	1
C4	CGA2B3X7R1E104KT0 Y0F	TDK	CAP, 100nF/25V, ±10%, X7R	1
C5, C6	CC0603KRX5R8BB225	YAGEO	CAP, 2.2uF/25V, ±10%, X5R	2
C7	TMK107BJ105KA-T	TAIYO YUDEN	CAP, 1uF/25V, ±10%, X5R	1
C8, C9	CC0603KRX7R8BB104	YAGEO	CAP,100nF/25V, ±10%, X7R	2
C10, C11, C12, C13, C14, C15, C16, C17, C18, C19	GCM21BC72A105KE36	MURATA	CAP,1uF/100V, ±10%, X7S	10
C20, C21, C22, C23, C24, C25, C26	CL10B104KC8NNNC	SAMSUNG	CAP,100nF/100V, ±10%, X7R	7
C27, C28,C30,C31,C34	GRM32EC72A106KE05 K	MURATA	CAP,10uF/100V, ±10%, X7S	5
C29,C32,C33	EMPTY		САР	3
R1, R4	RC0402FR-072R2L	YAGEO	Res, 2.2Ω, ±1%	2
R2, R3, R5, R17, R18	RC0402JR-070RL	YAGEO	Res, 0Ω, ±1%	5
R6, R9, R13	ERJ3GEY0R00V	PANASONIC	Res, 0Ω, 100mW	3
R7, R8	ERA3AEB103V	PANASONIC	Res, 10KΩ, ±0.1%	2
R10, R11, R14, R15, R19	ЕМРТҮ		Res	5
R12	RC0603FR-07200RL	YAGEO	Res, 200Ω, ±1%	1
R16	RC0603FR-07360RL	YAGEO	Res, 360Ω, ±1%	1
R20, R21	ERA2AED103X	PANASONIC	Res, 10KΩ, ±0.5%	2
L1	EMPTY		Inductance	1
D3, D4	SDM03U40-7	DIODES	Schottky, 30V, 30mA	2
Q1, Q2	INN100W027A	INNOSCIENCE	GAN FETs, 100V/2.7mΩ	2
U1	uP1966E	UPI SEMICONDUCTOR	Dual-Channel Gate Driver	1
U2	TPS70950DBVR-TP	TECH PUBLIC	LDO voltage regulators , fixed 5V output,	1
U3	SN74LVC1G08DBVR	TEXAS INSTRUMENTS	Single 2-Input Positive-AND Gate	1
U4	NC7SZ00M5X	ONSEMI	Two-Input NAND Gate	1



Revision History

Date	Versions	Description	Author
2023-09-08	1.0	First edition	AE Team
2025-03-07	5-03-07 1.1	Format modification,	AE Team
		content optimization	AE TEAIT



Note:

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